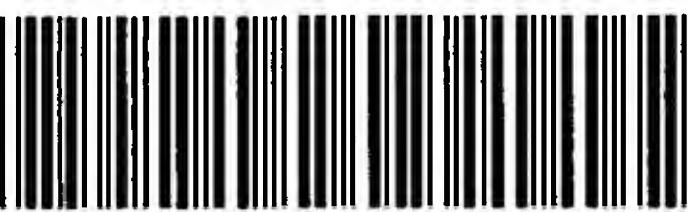


Search Notes



Application/Control No.

10/604.166

Examiner

Tae H. Yoon

**Applicant(s)/Patent under
Reexamination**

SINGH ET AL

Art Unit

1714

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)